

Electronic Patent Application Fee Transmittal

Application Number:	10544178			
Filing Date:	24-Apr-2006			
Title of Invention:	INSPECTION METHOD, MANUFACTURING METHOD OF PIECE FOR ANALYSIS, ANALYSIS METHOD, ANALYZER, MANUFACTURING METHOD OF SOI WAFER, AND SOI WAFER			
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Filer:	Robert Charles Friedt Perez/Shylah Dobson			
Attorney Docket Number:	061063-0317066			
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Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
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